

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination AHN ET AL.	
		Examiner Lixi Chow	Art Unit 2652	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0003762	01-2002	Dekker, Martijn Jeroen	369/53.3
	B	US-2002/0101808	08-2002	Seo, Jin-gyo	369/59.11
	C	US-5,291,470	03-1994	Nishiuchi et al.	369/59.11
	D	US-6,396,792	05-2002	Ichihara, Katsutaro	369/116
	E	US-5,150,351	09-1992	Ohno et al.	369/116
	F	US-2002/0001275	01-2002	Tanaka et al.	369/59.12
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.